### SN74ALVCH16334 16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS

SCES090 - OCTOBER 1996

- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Member of the Texas Instruments Widebus™ Family
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

### description

This 16-bit universal bus driver is designed for 2.3-V to 3.6-V V<sub>CC</sub> operation.

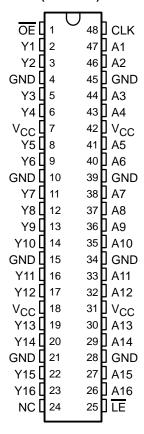
Data flow from A to Y is controlled by the output-enable  $(\overline{OE})$  input. The device operates in the transparent mode when the latch-enable  $(\overline{LE})$  input is low. The A data is latched if the clock (CLK) input is held at a high or low logic level. If  $\overline{LE}$  is high, the A-bus data is stored in the latch/flip-flop on the low-to-high transition of CLK. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16334 is available in TI's shrink small-outline (DL) and thin shrink small-outline (DGG) packages, which provide twice the I/O pin count and functionality of standard small-outline packages in the same printed circuit board area.

The SN74ALVCH16334 is characterized for operation from –40°C to 85°C.

## DGG OR DL PACKAGE (TOP VIEW)



NC - No internal connection



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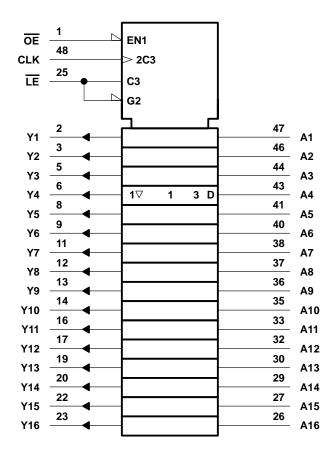


### **FUNCTION TABLE**

	INP	UTS		OUTPUT		
OE	LE	CLK	Α	Y		
Н	Х	Х	Х	Z		
L	L	Χ	L	L		
L	L	X	Н	Н		
L	Н	$\uparrow$	L	L		
L	Н	$\uparrow$	Н	Н		
L	Н	Н	Χ	Y <sub>0</sub> †		
L	Н	L	Χ	Y <sub>0</sub> ‡		

<sup>†</sup> Output level before the indicated steady-state input conditions were established, provided that CLK is high before LE goes low

### logic symbol§

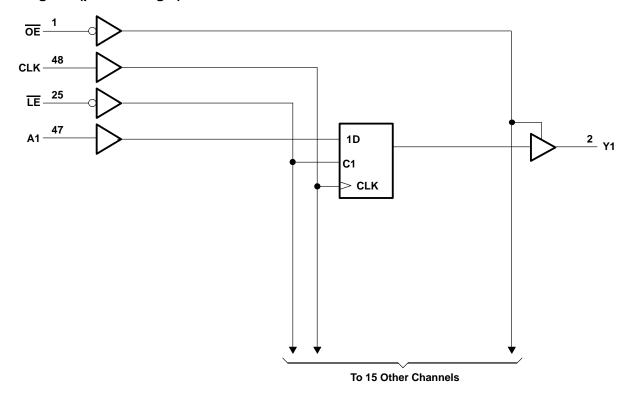


§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



<sup>‡</sup> Output level before the indicated steady-state input conditions were established

### logic diagram (positive logic)



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	
Input voltage range, V <sub>I</sub> (see Note 1)	
Output voltage range, V <sub>O</sub> (see Notes 1 and 2)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{ K }(V_{ C } < 0)$	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±50 mA
Continuous current through each V <sub>CC</sub> or GND	±100 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 3): DGG package	e 0.85 W
DL package	1.2 W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
  - 2. This value is limited to 4.6 V maximum.
  - 3. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the *ABT Advanced BiCMOS Technology Data Book*.



# SN74ALVCH16334 16-BIT UNIVERSAL BUS DRIVER WITH 3-STATE OUTPUTS SCES090 - OCTOBER 1996

## recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vcc	Supply voltage		2.3	3.6	V
V	High-level input voltage Low-level input voltage Input voltage Output voltage High-level output current Low-level output current	V <sub>CC</sub> = 2.3 V to 2.7 V	1.7		V
VIH		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		V
V	Low lovel input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	V
VIL	<ul> <li>High-level input voltage</li> <li>Low-level input voltage</li> <li>Input voltage</li> <li>Output voltage</li> <li>High-level output current</li> <li>Low-level output current</li> <li>Low-level output rarent</li> <li>Input transition rise or fall rate</li> </ul>	V <sub>CC</sub> = 2.7 V to 3.6 V		0.8	V
٧ <sub>I</sub>	Input voltage		0	Vcc	V
٧o	Output voltage		0	Vcc	V
		V <sub>CC</sub> = 2.3 V		-12	
ЮН	H High-level input voltage  L Low-level input voltage  Input voltage  Output voltage  High-level output current  Low-level output current  In Low-level output current	V <sub>CC</sub> = 2.7 V		-12	mA
		VCC = 3 V		-24	
		V <sub>CC</sub> = 2.3 V		12	
lOL	Low-level output current	V <sub>CC</sub> = 2.7 V		12	mA
	/IH High-level input voltage  /IL Low-level input voltage  /I Input voltage  /O Output voltage  OH High-level output current  OL Low-level output current  tt/Δv Input transition rise or fall rate	V <sub>CC</sub> = 3 V		24	
Δt/Δν	Input transition rise or fall rate		0	10	ns/V
TA	Operating free-air temperature		-40	85	°C

NOTE 4: Unused inputs must be held high or low to prevent them from floating.



# PRODUCT PREVIEW

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	RAMETER	TEST CO	ONDITIONS	VCC	MIN	TYP†	MAX	UNIT
		I <sub>OH</sub> = -100 μA		2.3 V to 3.6 V	V <sub>CC</sub> -0.	.2		
VOH  VOL	$I_{OH} = -6 \text{ mA},$	V <sub>IH</sub> = 1.7 V	2.3 V	2				
\ \ <sub>\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\</sub>			V <sub>IH</sub> = 1.7 V	2.3 V	1.7			V
VOH		I <sub>OH</sub> = -12 mA	V <sub>IH</sub> = 2 V	2.7 V	2.2			V
			V <sub>IH</sub> = 2 V	3 V	2.4			
		$I_{OH} = -24 \text{ mA},$	V <sub>IH</sub> = 2 V	3 V	2			
		I <sub>OL</sub> = 100 μA		2.3 V to 3.6 V			0.2	
		$I_{OL} = 6 \text{ mA},$	V <sub>IL</sub> = 0.7 V	2.3 V			0.4	
VOL		I <sub>OL</sub> = 12 mA	V <sub>IL</sub> = 0.7 V	2.3 V			0.7	V
		IOL = 12 IIIA	V <sub>IL</sub> = 0.8 V	2.7 V			0.4	
		I <sub>OL</sub> = 24 mA,	V <sub>IL</sub> = 0.8 V	3 V			0.55	
IĮ		$V_I = V_{CC}$ or GND		3.6 V			±5	μΑ
		V <sub>I</sub> = 0.7 V		2.3 V	45			
		V <sub>I</sub> = 1.7 V		2.3 V	-45			
I <sub>hold</sub>		V <sub>I</sub> = 0.8 V		3 V	75			μΑ
		V <sub>I</sub> = 2 V		3 V	-75			
		$V_1 = 0 \text{ to } 3.6 \text{ V}^{\ddagger}$		3.6 V			±500	
loz§		$V_O = V_{CC}$ or GND		3.6 V			±10	μΑ
Icc		$V_I = V_{CC}$ or GND,	I <sub>O</sub> = 0	3.6 V			40	μΑ
∆lcc		One input at V <sub>CC</sub> – 0.6 V,	Other inputs at V <sub>CC</sub> or GND	3 V to 3.6 V			750	μΑ
VOL  II  Ihold  IOZ  ICC  ΔICC  Ci	Control inputs	V. Vaa or CND		221	0.01/			~F
	Data inputs	V <sub>I</sub> = V <sub>CC</sub> or GND		3.3 V	3.3 V			pF
Co	Outputs	$V_O = V_{CC}$ or GND		3.3 V				pF

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{CC} = 3.3 \text{ V}$ .

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency								MHz
	Pulse duration	LE low							
t <sub>W</sub>		CLK high or low							ns
	Setup time	Data before CLK↑							
t <sub>su</sub>		Data before LE↑, CLK high							ns
		Data before LE↑, CLK low							
+.	Hold time	Data after CLK↑							20
t <sub>h</sub>	HOIU IIIIIE	Data after LE↑, CLK high or low							ns

<sup>‡</sup> This is the bus-hold maximum dynamic current required to switch the input from one state to another.

<sup>§</sup> For I/O ports, the parameter IOZ includes the input leakage current.

## **SN74ALVCH16334 16-BIT UNIVERSAL BUS DRIVER** WITH 3-STATE OUTPUTS SCES090 – OCTOBER 1996

### switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 and 2)

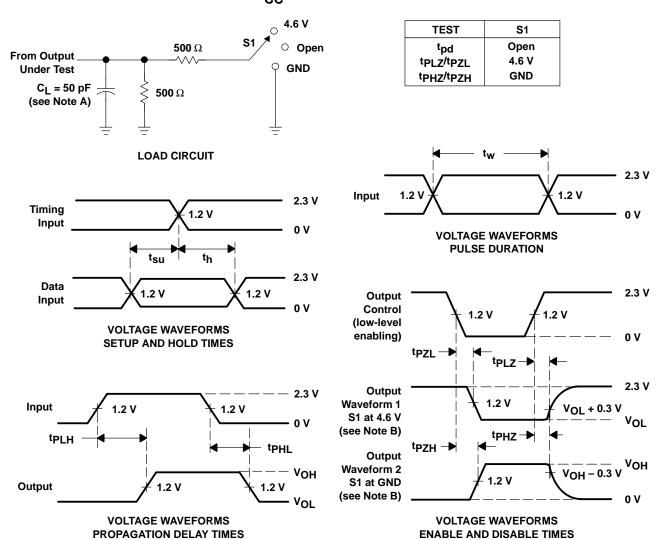
PARAMETER	FROM (INPUT)	TO VCC = 2.9 ± 0.2 V		CC = 2.5 V ± 0.2 V V <sub>CC</sub> = 2.7 V		UNIT
	(INPUT)	(001701)	MIN MAX	MIN MAX	MIN MAX	
f <sub>max</sub>						MHz
	Α	Υ				
t <sub>pd</sub>	LE	Y				ns
·	CLK	Y				
t <sub>en</sub>	ŌĒ	Y				ns
<sup>t</sup> dis	ŌĒ	Y				ns

## operating characteristics, $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 2.5 V ± 0.2 V	V <sub>CC</sub> = 3.3 V ± 0.3 V	UNIT	
				TYP	TYP	
C .	Power dissipation capacitance	Outputs enabled	C <sub>I</sub> = 0, f = 10 MHz			ρF
C <sub>pd</sub>	Fower dissipation capacitance	Outputs disabled	$C_L = 0$ , $f = 10 MHz$			рг



# PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.5 V $\pm$ 0.2 V

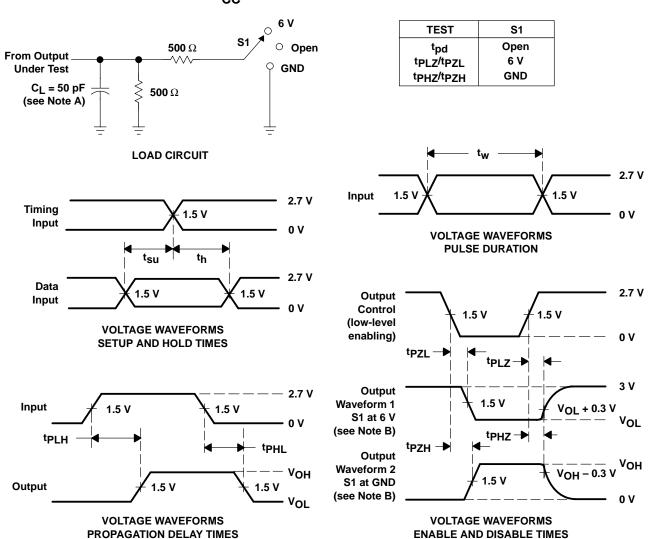


NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

### PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.7 V AND 3.3 V $\pm$ 0.3 V



- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
  - D. The outputs are measured one at a time with one transition per measurement.
  - E. tpLz and tpHz are the same as tdis.
  - F. tpzL and tpzH are the same as ten.
  - G. tplH andtpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



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